

Room Temperature Optically Pumped 2.56- μm Lasers With “W” Type InGaAs/GaAsSb Quantum Wells on InP Substrates

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Abstract—The optically pumped laser using InGaAs/GaAsSb W-type quantum wells is demonstrated with a threshold power density $\sim 40 \text{ kW/cm}^2$. The L-L curve and the dramatic line width shrinkage above threshold confirm, for the first time, mid-infrared lasing in this structure on InP substrates. The lasing wavelength at 2.56 μm is the longest lasing wavelength at room temperature for the interband transition of InP-based material system.

Index Terms—InP-based, midinfrared lasers, optically pumped, type-II “W” type quantum wells.

I. INTRODUCTION

MIDINFRARED (mid-IR) lasers with wavelengths longer than 2 μm have applications in many different areas such as environmental monitoring, communications, life science, and molecular spectroscopy [1]. For the development of semiconductor mid-IR lasers, the InP substrate is a suitable platform due to its well established process technology, better wafer quality and lower cost compared to the conventionally used InAs and GaSb substrates. InAs/InGaAs type-I quantum wells (QWs) have been used to realize mid-infrared lasers on InP substrates [2]. However, it is difficult to extend the lasing wavelength beyond $\sim 2.3 \mu\text{m}$ due to the highly-strained structures. The “W” type QWs with the type II staggered band alignment using InGaAs/GaAsSb have been shown to be able to extend the lasing wavelength in the midinfrared range [3]. The high In-content and dilute nitride InGaNAs/GaAsSb type-II “W” QWs have also been designed and employed for the 1.55 μm light emitting on GaAs substrates, and have been proposed for mid-IR lasers on InP substrates [4]–[9]. But most of mid-IR lasers were done on the lattice matched system using InAs/InGaSb structures on GaSb substrates [10]–[12]. In our previous study, we have obtained intense mid-IR photoluminescence from samples with properly designed “W” type QWs on InP substrates [13]. In this

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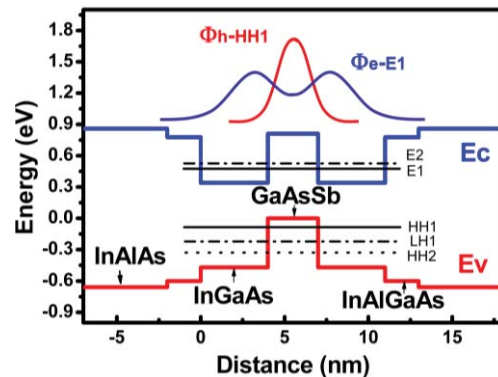


Fig. 1. Energy band diagram of the “W” type QW with the wavefunctions for lowest quantized electron (E1) state and hole (HH1) state.

letter, for the first time, we successfully demonstrated the room temperature optically-pumped mid-IR lasers with the emission wavelength up to 2.56 μm on InP substrates using InGaAs/GaAsSb “W” type QWs.

The “W” structure consists of symmetric InGaAs/GaAsSb/InGaAs layers, which are sandwiched between In(Ga)AlAs barrier layers. The “W” band alignment, named from the shape of the conduction band profile, along with the electron and hole wavefunctions for our samples are illustrated in Fig. 1. Because of the type-II band alignment, the hole wavefunction is confined inside the GaAsSb QW; while the electron wavefunction is located in the two adjacent but coupled InGaAs QWs, which have the split symmetric (E1) and anti-symmetric (E2) states. This band alignment allows a smaller optical transition energy than the bandgap energies of the constituent layers, and therefore giving a longer emission wavelength. A general problem in the type-II structures is the small electron-hole wavefunction overlap, which results in a lower optical transition rate. This adverse effect, however, can be greatly reduced by using properly designed barrier layers in the “W” structure to provide quantum confinement for the electrons. The “W” structure preserves the two dimensional densities of states for both carriers, and the type II configuration suppresses the Auger recombination [10], [14].

The samples used in this letter were grown on S-doped (001) InP substrates by a Veeco GEN II molecular beam epitaxy system equipped with needle valve controlled As and Sb cracking cells. The group V species of As₂ and Sb₂ were used during the growth process. The active region of the laser diode had 15 stacks of the “W” QWs with each consisting

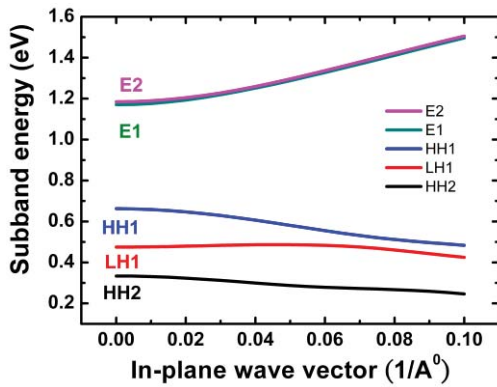


Fig. 2. Band structure of the designed “W” type QW based on the 8-band $k \cdot p$ model.

of a symmetric $\text{In}_{0.53}\text{Ga}_{0.47}\text{As}/\text{GaAs}_{0.25}\text{Sb}_{0.75}/\text{In}_{0.53}\text{Ga}_{0.47}\text{As}$ (4/3/4nm) structure sandwiched between two 2 nm $\text{In}_{0.36}\text{Al}_{0.32}\text{Ga}_{0.32}\text{As}$ strain-compensated layers. The stacks were separated by 5 nm $\text{In}_{0.52}\text{Al}_{0.48}\text{As}$ barrier layers. The active region had a total thickness of $\sim 300\text{nm}$ and was grown at 460°C . The bottom and top optical cladding layers were made of lattice-matched $\text{In}_{0.52}\text{Al}_{0.48}\text{As}$ grown at 500°C . Taking advantage of the lower refractive index of the InP substrate, only $0.3\mu\text{m}$ bottom cladding layer was used. The top cladding layer had a thickness of $2.25\mu\text{m}$ and was capped by a 100 nm $\text{In}_{0.53}\text{Ga}_{0.47}\text{As}$ layer.

We have theoretically calculated the band structure of our “W” type QW using an 8-band $k \cdot p$ theory. The result is shown in Fig. 2. The material parameters used in the calculation were taken from the published literature [15]. Based on the calculation, the effective band gap is found to be $\sim 0.51\text{eV}$. Because of the coupling between the two InGaAs electron QWs, there is a small energy splitting of $\sim 17\text{meV}$ between the symmetric E1 and the anti-symmetric E2 bands at the Brillouin zone center. The energy separation between the first heavy hole (HH1) band and the first light hole (LH1) band, however, has a large value of $\sim 188\text{meV}$, which is due to the small width of the hole QW and the large valence band offset of the InGaAs/GaAsSb type-II structure. The calculated wave function overlap between E1 and HH1 is 0.27, and the overlap between E2 and HH1 is zero due to the anti-symmetric nature of the E2 wavefunction. The in-plane effective masses determined via parabolic curve fitting are $0.075m_0$ for the E1 band edge and $0.103m_0$ for the HH1 band edge at the zone center. The greatly reduced heavy hole effective mass is attributed to the compressively strained GaAsSb layer. This could lead to a lower transparency carrier density and a higher differential gain for the laser operation.

The sample was cleaved to form a 1 mm long cavity and optically pumped by a 1064nm ($\sim 1.2\text{eV}$) pulsed fiber laser shaped via two cylindrical lenses, resulting in a beam size of $\sim 200\mu\text{m}$ (width) \times 3mm (length). The long axis of the pump beam was aligned in parallel with the cavity direction. The pumping light penetrated the thick InAlAs ($\sim 1.5\text{eV}$) cladding layer and was absorbed by the active region. Using separate measurements of the transmission and reflection of samples with and without the epilayers, we estimated that around 25%

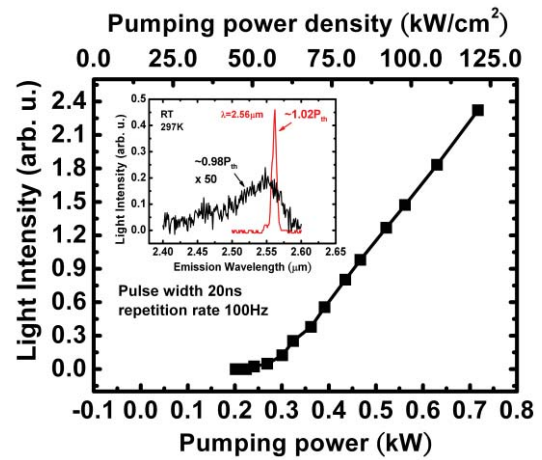


Fig. 3. L-L curve of a 1-mm-long “W” type laser at room temperature. The inset figure is the lasing spectra at $\sim 0.98 P_{th}$ (intensity 50x) and $\sim 1.02 P_{th}$.

of the pumping light was absorbed by the active region. The 15 stacks of “W” QWs also form an optical waveguide for the laser cavity. The light output from the cleaved mirror went through a long-pass filter and two focusing lenses. It then was dispersed through a monochromator and detected by a thermal electric cooled InGaAsSb photodetector. The room temperature lasing behavior is shown in Fig. 3. The L-L curve was measured under pulsed operation with 20 ns pumping pulses at a 100 Hz repetition rate. The lasing phenomenon is confirmed by the dramatically increased output power as well as the abruptly shrunk spectrum after a threshold power density (P_{th}) of $\sim 40\text{ kW/cm}^2$. Taking into account of the surface reflection and the percentage of the power absorbed, the absorbed threshold power density per well is $\sim 0.467\text{ kW/cm}^2$. The spectra at $0.98P_{th}$ and $1.02P_{th}$ are shown in the inset of Fig. 3. The lasing wavelength is at $2.56\mu\text{m}$ corresponding to the transition between the lowest E1 state and the first quantized heavy hole state (HH1). We have measured L-L curves of lasers with different cavity length (L) to extract internal loss (α_i), which is around 10.7cm^{-1} at room temperature.

In order to further characterize our laser, we have measured the lasing performance at different temperatures. The temperature dependent L-L curves are plotted in Fig. 4. The extracted P_{th} as a function of temperature is shown in the inset (in log scale). It is found that the slope efficiency hardly changes for temperatures below 250K. The slowly increased P_{th} from 78K to 250K has an exponentially fitted characteristic temperature (T_0) of 487.8K. However, when the temperature is increased above 250K, the slope efficiency decreases and the threshold power increases at a much faster rate. The characteristic temperature is 41.8K when the temperature goes beyond 250K. It is known that the monomolecular (Shockley-Read) recombination and the radiative recombination are dominating processes at low temperatures. But they could not lead this T_0 change behavior because the Shockley-Read coefficient varies with $\sim T^{1/2}$ and the radiative coefficient gradually decays with T. The leakages of escaped carriers should also not play a role here since both the E1 level in the conduction

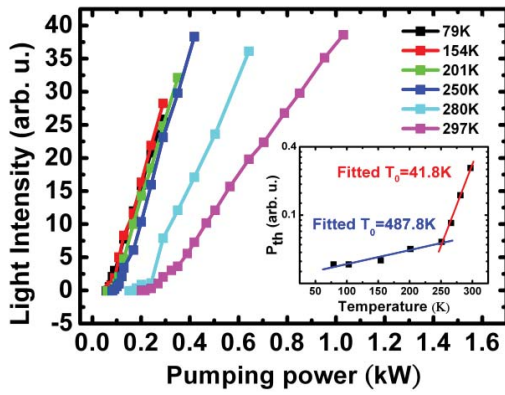


Fig. 4. L-L curves measured at different temperatures. The inset shows the plot of P_{th} as a function of temperature.

band and the HH1 level in the valence band are more than 300meV deep compared to the surrounding potential barriers. The most probable reason for the rapid increase of threshold power density after $\sim 250\text{K}$ is the Auger processes. The amount of the Auger effect for our laser is analyzed in the following.

We first calculated the laser's modal gain as a function of carrier density for a single "W" quantum well using the 8-band $k.p$ method including a Lorentzian line broadening function. The theoretically obtained 2D transparency carrier density was $\sim 1.1 \times 10^{12} \text{cm}^{-2}$. Based on the measured internal loss and the calculated modal gain, we estimated a 2D threshold density $\sim 1.6 \times 10^{12} \text{cm}^{-2}$ per well at room temperature. Since multiple quantum wells have higher optical gain and a larger optical confinement factor, the threshold carrier density should be lower than this number. Taking $N_{th} = 1.1 \sim 1.6 \times 10^{12} \text{cm}^{-3}$, we can estimate the carrier life time (τ_{th}) at threshold using the relation, $\tau_{th} \approx N_{th} \hbar \omega_p / P_{th} f_{ab} (1-R)$, where N_{th} , $\hbar \omega_p$, f_{ab} , and R refer to the 2D threshold current density, the photon energy of the pump beam, the absorbed fraction, and the surface reflectivity, respectively. The obtained τ_{th} is in the range of 0.44~0.64 ns. This will lead to an Auger coefficient, $\gamma \sim 1/\tau_{th} (N_{th}/d)^2$, in the range of $1.37 \sim 4.21 \times 10^{-27} \text{cm}^6/\text{s}$ at room temperature, where d of 15nm is used here for the thickness of one period "W" QW. This relatively high Auger coefficient explains why T_0 goes down at high temperatures. The value obtained is comparable to those in InAs/InGaSb type-II quantum wells on GaSb substrate, which also show similar T_0 at room temperatures [10], [14].

II. CONCLUSION

In conclusion, for the first time we have demonstrated the room temperature optically-pumped mid-IR "W" type lasers

on InP substrates. The lasing wave length is 2.56 μm with a threshold pumping power density of $\sim 40 \text{kW}/\text{cm}^2$. The laser shows a characteristic temperature (T_0) of 487.8K when it is operated below 250K and a T_0 of 41.8K near room temperature. The small T_0 at room temperature is considered due to the dominated Auger processes. An Auger coefficient in the range of $1.37 \sim 4.21 \times 10^{-27} \text{cm}^6/\text{s}$ was estimated. More studies are needed to improve the laser performance. We believe that the "W" structure on InP substrates are promising for the fabrication of mid-IR optoelectronics devices.

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